



## INVITATION FOR AN OPEN WORKSHOP ON AIRPORT SECURITY *APPLICATIONS & IMPLICATIONS OF HUMAN FACTORS ON AIRPORT SECURITY*

*May 25, 2011, Brussels, Belgium*

The BEMOSA Consortium, a consortium consisting of 11 partners from 9 different countries within the EU Seventh Framework Programme for Research & Technology Development ("FP7"), has the pleasure to announce an open workshop **on applying human factors to airport security**. The workshop will discuss **the implications of such applications on the operation, legislation and training** of airport employees as well venues for further research.

The BEMOSA Consortium would like to invite **all relevant stakeholders** in order present our results to-date and in particular to present the principles of social networking applied to airport security. Stakeholders will include airport management officials responsible for security, human resources and operations; providers of airport security services; providers airport security training services as well as public officials & policy makers. **Through this workshop the BEMOSA Consortium will be able to obtain an evaluation by experts of the principles of applying human factors and social networking to security and comments from stakeholders.**

The workshop will be held in Room SDR1 of Building CDMA (Floor -1) of the European Commission, Rue du Champs de Mars 21 in Brussels. Registration is obligatory, but free of charge. The workshop will take place during the entire day, but lunch will be included. People interested to participate can register through our website <http://bemosa.technion.ac.il> not later than **May 18, 2011**.

We are looking forward to see you in Brussels!

On behalf of the BEMOSA Consortium,

Simon van Dam

Phone: +972-2-6786120

E-mail: [simonvd@trdf.technion.ac.il](mailto:simonvd@trdf.technion.ac.il)

Visit our website at <http://bemosa.technion.ac.il>

*Please register before May 18, 2011 through <http://bemosa.technion.ac.il> or send an e-mail to [simonvd@trdf.technion.ac.il](mailto:simonvd@trdf.technion.ac.il)*

*Registration is free of charge*